

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 248430US6		SERIAL NO. 10/768,088	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Ken IIZUKA			
				FILING DATE February 2, 2004		GROUP 2624	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	2002/90109	7/11/02	WENDT			
	AB	2003/39405	2/27/03	OOSAWA			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	JP 10-124667	5/15/98	JAPAN (w/ English Abstract)			X
	AP	JP 2000-268178	9/29/00	JAPAN (w/ English Abstract)			X
	AQ	JP 2003-153082	5/23/03	JAPAN (w/ English Abstract)			X
	AR	JP 3254622	11/30/01	JAPAN (w/ English Abstract)			X
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Hiroshi Sasaki, Koji Kobayashi, Takafumi Aoki, Masayuki Kawamata, Tatsuo Higuchi, "The Measurement of Rotation Angle of the Image by the Rotation Invariant Phase-Limited Correlation," Institute of Image Information and Television Engineers technical report, Japan, Institute of Image Information and Television Engineers, September 14, 1998, Vol. 22, No. 45, p. 55-60					
	AX	Nobuhumi Sasaki, Kenji Takita, Takafumi Aoki, Tatsuo Higuchi, Koji Kobayashi, "High Accuracy Registration based on the Phase-limited Correlation Method," Institute of Electronics, Information and Communication Engineers Technical Study Reports [Imaging Engineering], Japan, Institute of Electronics, Information and Communication Engineers, April 11, 2002, Vol. 102, No. 11, p. 49-54, IE2002-9					
	AY	Yagi, "Image Processing and Lighting 4, Correlation of the Fluctuation of Lighting Part (2)," Image Information, Japan Industry Development Organization, July 1, 2000, Vol. 32, No. 13, p. 48-53, 92					
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							